


Device Type	V_{RRM} (1)	V_{DRM} (1)	V_{RSM} (1)
KK2700/18	1800	1800	2000
KK2700/20	2000	2000	2100

V_{RRM} = Repetitive peak reverse voltage
 V_{DRM} = Repetitive peak off state voltage
 V_{RSM} = Non repetitive peak reverse voltage (2)

Repetitive peak reverse leakage and off state leakage I_{RRM}/I_{DRM} 5 mA
80 mA (3)

Critical rate of voltage rise dv/dt (4)

Peak gate power dissipation	P_{GM}		20		W	
Average gate power dissipation	$P_{G(AV)}$		4		W	
Gate-trigger current	I_{GT}		150		mA	$V_D=12V; R_L=30\text{ohms}; T_j=+25^\circ\text{C}$
Gate- trigger voltage	V_{GT}	0.70	2.5		V	$V_D=12V; R_L=30\text{ohms}; T_j=+25^\circ\text{C}$
Peak negative voltage	V_{GRM}		5		V	

Delay time	t_d		3.0	2.5	s	$I_{TM}=1000A; V_D=67\%V_{DRM}$ Gate pulse: $V_G=30V; R_G=10\text{ohms};$ $t_r=0.1\text{ s}; t_p=20\text{ s}$
Turn-off time (with $V_R = -5\text{ V}$)	t_q		40		s	$I_{TM} =2500\text{ A}; di/dt =-25\text{ A/ s};$ $V_R =50\text{ V}; dv/dt=30V/ \text{ s};$ $V_D= 67\%V_{DRM}; T_j=125^\circ\text{C}$
Reverse recovery charge	Q_{rr}				C	$I_{TM}=2500\text{ A}; di/dt=-10A/ \text{ s};$ $V_R=50\text{ V}; T_j=125^\circ\text{C}$

Operating temperature	T_j	-40	+125		$^\circ\text{C}$	
Storage temperature	T_{stg}	-40	+140		$^\circ\text{C}$	
Thermal resistance - junction to case	$R_{(j-c)}$		0.01		$^\circ\text{C/W}$	Double sided cooled
Thermal resistance - case to heatsink	$R_{(c-s)}$		0.003		$^\circ\text{C/W}$	Double sided cooled
Mounting force	F	33	37	35	kN	

